

| Form PTO-1449<br>(REV. 1/06)  |          |  | US Dept. of Commerce<br>PATENT & TRADEMARK OFFICE | ATTY DOCKET NO.<br>128985     | APPLICATION NO.<br>10/588,146                       |
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|   |          |  | FILING DATE<br>August 1, 2006                     | GROUP<br>2852                 |   |
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